

IANDIORIO & TESKA

INTELLECTUAL PROPERTY LAW ATTORNEYS

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January 14, 2005

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

SUBJECT: Appli

Applicant:

Dubé et al.

Serial No.:

10/601,606

Filed:

June 23, 2003

For:

INTEGRATED ELECTROFLUIDIC SYSTEM AND METHOD

Docket No.: DR-352J

Dear Sir:

Pursuant to 37 CFR 1.56, enclosed are an Information Disclosure Citation in an Application, Form PTO-A820, and copies of 46 references.

This Information Disclosure Citation is timely filed and should be considered as it is filed before the mailing date of the first Office Action on the merits of the subject application pursuant to 37 CFR §1.97(b)(3).

If for any reason this Information Disclosure Citation is incomplete, or if at any time it appears that a Telephone Conference with counsel would help advance prosecution, please telephone the undersigned or his associates, collect in Waltham, Massachusetts at (781) 890-5678.

If any payment during prosecution is found to be incorrect, please charge any deficiency or credit any overpayment to by Deposit Account No. 09-0002. A copy of this letter is enclosed for use by the Finance Branch in the event that it is necessary to make any charge or credit to my deposit account.

Kindly acknowledge receipt of the foregoing by returning the enclosed self-addressed postcard.

Sincerely.

Jason/D. Skansko Reg No. 43 915

JDS/mgt Enclosures

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the U.S. Postal Service as first class mail in an envelope addressed to Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on *January 14*, 2005.

Marianne G. Tarczal

ATTY DOCKET NO. SERIAL NO. 10/601,606 DR-352J ORMATION DISCLOSURE CITATION Dubé et al. (Use several sheets if necessary) FILING **GROUP** June 23, 2003 3641 **U.S. PATENT DOCUMENTS** FILING DATE CLASS SUBCLASS DATE NAME DOCUMENT NUMBER IF APPROPRIATE INITIAL Jan-8-02 Nagle et al. 436 174 6,337,212 Wolk et al. 204 600 Nov-27-01 6,322,683 Nov-27-01 137 833 6,321,791 Chow 29 890.124 6,293,012 Sep-25-01 Moles 422 102 Jun-26-01 Dubrow et al. 6,251,343 422 177 Mar-13-02 Tonkovich et al. 6,200,536 497 Feb-6-01 **McReynolds** 156 6,182,733 428 458 6,156,438 Dec-5-00 Gumm et al. 49 Oct-24-00 Mastrangelo et al. 216 6,136,212 292 Sep-26-00 Gandhi et al. 156 6,123,798 Aug-15-00 Higdon et al. 137 341 6,102,068 FOREIGN PATENT DOCUMENTS TRANSLATION SUBCLASS CLASS DOCUMENT NUMBER DATE COUNTRY YES NO WO 98/07069 19-Feb-98 WIPO OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) van den Berg et al.: "Micro Total Analysis Systems: Microfluidic Aspects, Integration Concept and Applications" Topics in Current Chemistry, Vol. 194, Springer Verlag Berlin Heidelberg 1998, pp. 22-49 Mensinger, et al.: "Microreactor with Integrated Static Mixer and Analysis System", 1995 Kluwer Academic Publishers, Printed in the Netherlands, pp. 237-243 van der Schoot et al.: "Microsystems for Analysis in Flowing Solutions" © 1995 Kluwer Academic Publishers, Printed in the Netherlands, pp. 181-190 Baltes et al.: "CMOS Integrated Microsystems and Nanosystems", Part of the SPIE Conference on Smart Electronics and MEMS, Newport Beach, California, March 1999, SPIE Vol. 3673, 0277-786X/99, pp. 2-10 **DATE CONSIDERED EXAMINER** *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-A820 (also form PTO-1449)

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